

4/16/2014



**RELIABILITY MONITOR REPORT
FOR**

Epson 0.4μm Silicon Gate CMOS (S4)

MAXIM INTEGRATED

**160 RIO ROBLES
SAN JOSE, CA 95134**

**This Report was prepared by
MAXIM INTEGRATED Reliability Engineering**

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX8939BEWV

The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 4651 QUANTITY: 48 FAILS: 0 FITS: 24.5

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2013 and 3/31/2014 .

Process Information:

Process Description: Epson 0.4µm Silicon Gate CMOS (S4)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE		MAX8939BEWV+T	135°C	500 HRS	48	0	EALB1Q001AQ
				Total:		0	

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